

Very High Speed 1K (3K) Gate CMOS FPGA

Features

- Very high speed
 - Loadable counter frequencies greater than 100 MHz
 - Chip-to-chip operating frequencies up to 85 MHz
 - Input + logic cell + output delays under 9 ns
- Unparalleled FPGA performance for counters, data path, state machines, arithmetic, and random logic
- High usable density
 - 8 x 12 array of 96 logic cells provides 3,000 total available gates
 - 1,000 typically usable "gate array" gates in 44- and 68-pin PLCC/ CPGA packages
- Low power, high output drive
 - Standby current typically 2 mA
 - 16-bit counter operating at 100 MHz consumes 50 mA
 - Minimum I_{OL} and I_{OH} of 8 mA
- Flexible logic cell architecture
 - Wide fan-in (up to 14 input gates)
 - Multiple outputs in each cell
 - Very low cell propagation delay (3.4 ns)
- Low-cost, powerful design tools
 - Designs entered in VHDL, schematics, or both
 - Fast, fully automatic place and route

- Waveform simulation with back annotated net delays
- -PC and workstation platforms
- Robust routing resources
 - Fully automatic place and route of designs using up to 100 percent of logic resources
 - No hand routing required
- 32 (CY7C381) to 56 (CY7C382) bidirectional input/output pins
- 6 dedicated input/high-drive pins
- 2 clock/dedicated input pins with fanout-independent, low-skew nets
 - Clock skew <1 ns
- Input hysteresis provides high noise immunity
- Thorough testability
 - Built-in scan path permits 100 percent factory testing of logic and I/O cells
 - Automatic Test Vector Generation (ATVG) software supports user testing after programming
- CMOS process with ViaLink[™] programming technology
 - High-speed metal-to-metal link
 - Non-volatile antifuse technology
- 68-pin PLCC is compatible with EPLD 1800 and LCA 2064 industrystandard pinouts

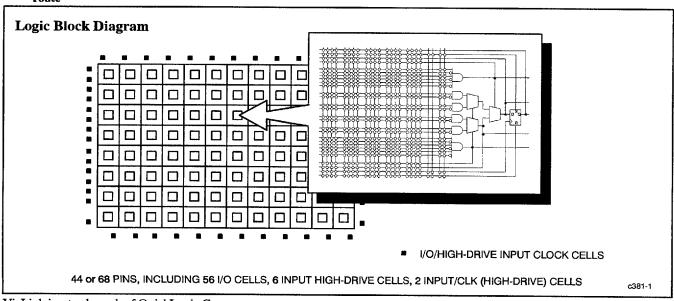
Functional Description

The CY7C381 and CY7C382 are members of the pASIC380 family of very high speed CMOS user-programmable ASIC (pASIC) devices. The 96 logic cell field-programmable gate array (FPGA) offers 1,000 typically usable "gate array" gates. This is equivalent to 3,000 EPLD or LCA gates. The CY7C381 is available in a 44-pin PLCC. The CY7C382 is available in a 68-pin PLCC and CPGA.

Low-impedance, metal-to-metal ViaLink interconnect technology provides non-volatile custom logic capable of operating at speeds above 100 MHz with input and output delays under 4 ns. This permits high-density programmable devices to be used with today's fastest CISC and RISC microprocessors.

Designs are entered into the CY7C381 and CY7C382 using Cypress's Warp3 software or one of several third-party tools. Warp3 is a sophisticated CAE package that features schematic entry, waveform-based timing simulation, and VHDL design synthesis. The CY7C381 and CY7C382 feature ample on-chip routing channels for fast, fully automatic place and route of high gate utilization designs.

For detailed information about the pASIC380 architecture, see the pASIC380 Family datasheet.



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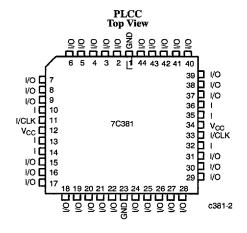
San Jose

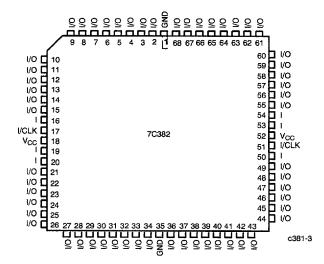
CA 95134 • 408-943-2600 June 1992 - Revised February 1994



Pin Configurations







Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature -65°C to +150°C Ceramic -40°C to +125°C
Lead Temperature 300°C
Supply Voltage0.5V to +7.0V
Input Voltage $-0.5V$ to $V_{CC} + 0.5V$
ESD Pad Protection ±2000 V
DC Input Voltage ±20 mA
Latch-Up Current ±100 mA

Operating Range

Range	Ambient Temperature	v _{cc}
Commercial	0°C to +70°C	5V ± 5%
Industrial	−40° to +85°C	$5 ext{V}\pm ext{10}\%$

Delay Factor (K)

Speed	Indu	strial	Comn	ercial
Speed Grade	Min.	Max.	Min.	Max.
-0	0.4	1.67	0.46	1.55
-1	0.4	1.43	0.46	1.33
-2	0.4	1.35	0.46	1.25
-3			0.46	1.15

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	$I_{OH} = -4.0 \mathrm{mA}$	3.7		V
		$I_{OH} = -8.0 \text{ mA}$	2.4		v
	1	$I_{\mathrm{OH}} = -10.0\mu\mathrm{A}$	$V_{\rm CC}-0.1$		V
v_{ol}	Output LOW Voltage	$I_{\rm OL}=8.0~{\rm mA}$		0.4	V
		$I_{OL} = 10.0 \mu\text{A}$		0.1	V
V_{IH}	Input HIGH Voltage		2.0		V
V_{IL}	Input LOW Voltage			0.8	V
I_{I}	Input Leakage Current	$V_{IN} = V_{CC}$ or GND	-10	+10	μA
I _{OZ}	Output Leakage Current	$V_{IN} = V_{CC}$ or GND	-10	+10	μA
I _{OS}	Output Short Circuit Current	$V_{OUT} = GND$	-10	-80	mA
		$V_{OUT} = V_{CC}$	30	140	mA
I_{CC1}	Standby Supply Current	V_{IN} , $V_{I/O} = V_{CC}$ or GND		10	mA
I_{CC2}	Supply Current ^[1, 2]	$f = 1.0 \text{ MHz}, V_I = V_{CC} \text{ or GND}$		20	mA



Capacitance

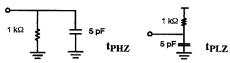
Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance ^[3]	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	10	pF
C _{OUT}	Output Capacitance	$V_{\rm CC} = 5.0 V$	20	pF

Switching Characteristics Over the Operating Range

		Propagation Delays ^[4] with Fanout of					
Parameter	Description	1	2	3	4	8	Unit
LOGIC CELI	S						
t _{PD}	Combinatorial Delay ^[5]	2.4	2.9	3.5	4.0	6.1	ns
t_{SU}	Set-Up Time ^[5]	2.7	2.7	2.7	2.7	2.7	ns
t _H	Hold Time	0	0	0	0	0	ns
t _{CLK}	Clock to Q Delay	2.4	2.9	3.4	3.9	6.0	ns
t _{SET}	Set Delay	3.4	4.0	4.6	5.1	7.4	ns
t _{RESET}	Reset Delay	3.6	4.0	4.5	5.0	6.9	ns
t _{CWHI}	Clock HIGH Time	2.0	2.0	2.0	2.0	2.0	ns
t _{CWLO}	Clock LOW Time	2.0	2.0	2.0	2.0	2.0	ns
t _{SW}	Set Width	2.1	2.1	2.1	2.1	2.1	ns
t _{RW}	Reset Width	1.9	1.9	1.9	1.9	1.9	ns
INPUT CELL	S						
$t_{\rm IN}$	Input Delay (HIGH Drive)	3.7	3.8	4.2	4.6	6.4	ns
t _{INI}	Input, Inverting Delay (HIGH Drive)	3.5	3.6	4.0	4.4	6.2	ns
t _{IO}	Input Delay (Bidirectional Pad)	2.6	3.1	3.6	4.1	6.2	ns
t _{GCK}	Clock Buffer Delay ^[6]	3.6	3.7	3.8	3.9		ns
OUTPUT CE	LLS	Propagation Delays ^[4] with Output Load Capacitance (pF) of				f	
		30	50	75	100	150	
toutlh	Output Delay LOW to HIGH	2.7	3.4	4.2	5.1	6.8	ns
t _{OUTHL}	Output Delay HIGH to LOW	2.7	3.5	4.6	5.7	7.9	ns
t _{PZH}	Output Delay Three-State to HIGH	4.0	4.9	6.1	7.3	9.7	ns
t _{PZL}	Output Delay Three-State to LOW	3.6	4.2	5.0	5.8	7.3	ns
t _{PHZ}	Output Delay HIGH to Three-State ^[7]	2.9					ns
t _{PLZ}	Output Delay LOW to Three-State ^[7]	3.3					ns

Notes:

- Measured with six 16-bit counters configured internally and all outputs driving. To calculate power for your application, see the "pAS-IC380 Power vs. Operating Frequency" application note in the Cypress Semiconductor Applications Handbook.
- 2. Guaranteed by design but not 100% tested.
- 3. $C_I = 20 \text{ pF max. on pin } 32 \text{ (7C381) or pin } 50 \text{ (7C382)}.$
- Worst-case propagation delay times over process variation at V_{CC} = 5.0V and T_A = 25°C. Multiply by the appropriate delay factor, K, for speed grade to get worst-case parameters over full V_{CC} and temperature range as specified in the operating range. All imputs are TTL with 3-ns linear transition time between 0 and 3 volts.
- These limits are derived from worst-case values for a representative selection of the slowest paths through the pASIC logic cell including net delays. Guaranteed delay values for specific paths should be determined from simulation results.
- Clock buffer fanout refers to the maximum number of flip-flops per half column. The number of half columns used does not affect clock buffer delay.
- 7. The following loads are used for t_{PXZ} :



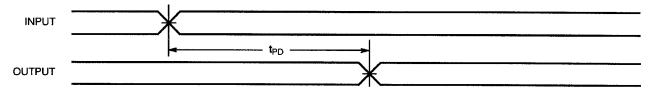


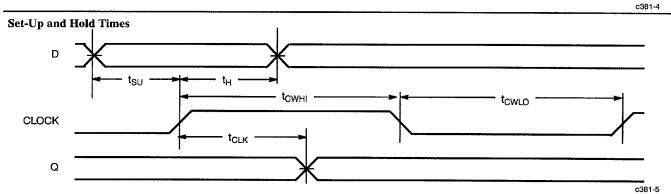
High Drive Buffer

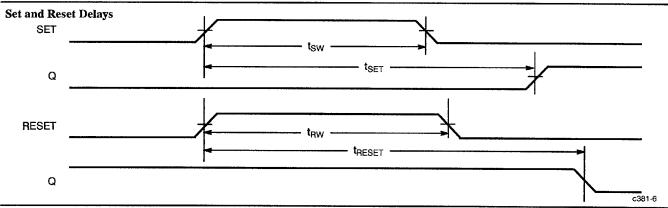
		# High Drives Wired		Propagation Delays ^[4] with Fanout of				
Parameter	Description	Together	12	24	48	72	96	Unit
t _{IN}	High Drive Input Delay	1	7.9	11.2				ns
		2		8.0	9.7			ns
		3			8.6	10.4	11.8	ns
		4				9.4	10.8	ns
t _{INI}	High Drive Input, Inverting Delay	1 .	7.5	10.8				ns
		2		7.5	9.3			ns
		3			8.2	10.0	11.8	ns
		4				9.0	10.8	ns

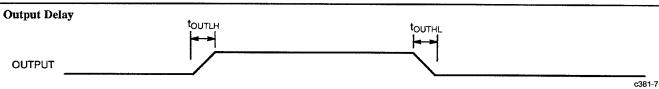
Switching Waveforms

Combinatorial Delay



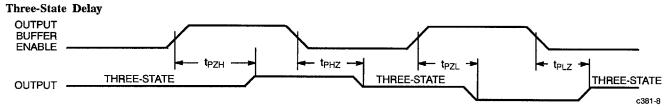








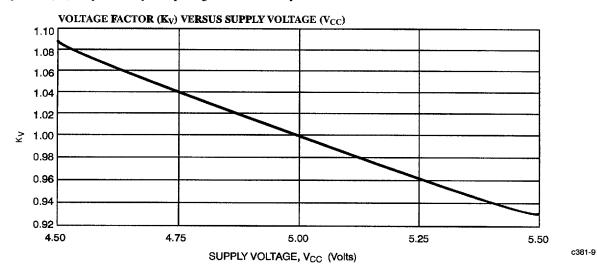
Switching Waveforms (continued)

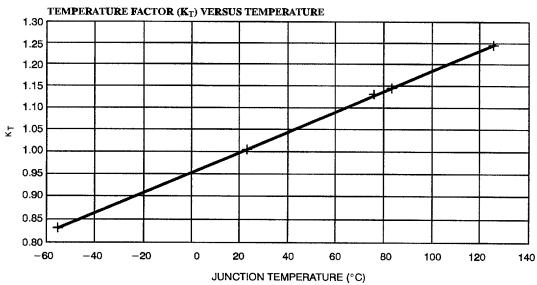


Typical AC Characteristics

Propagation delays depend on routing, fan-out, load capacitance, supply voltage, junction temperature, and process variation. The AC Characteristics are a design guide to provide initial timing estimates at nominal conditions. Worst-case estimates are obtained when nominal propagation delays are multiplied by the appropriate Delay Factor, K, as specified by the speed grade in the Delay

Factor table. The effects of voltage and temperature variation are illustrated in the graphs below. Warp3 incorporates datasheet AC Characteristics into the design database for pre-place-and-route simulations. The Warp3 Delay Modeler extracts specific timing parameters for precise simulation results following place and route.



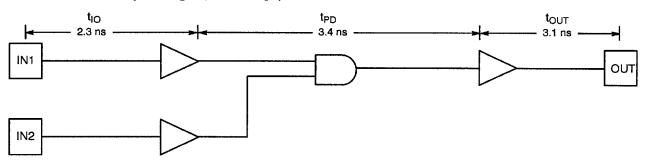


*THETA JA = 45 °C/WATT FOR PLCC

c381-10

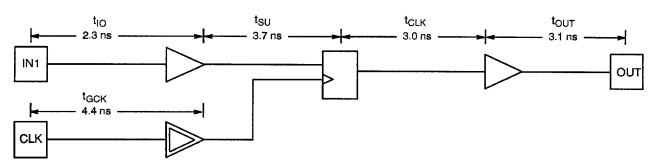


Combinatorial Delay Example (Load = 30 pF)



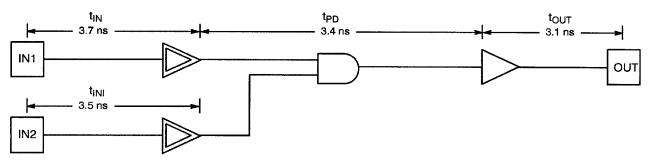
INPUT DELAY + COMBINATORIAL DELAY + OUTPUT DELAY = 8.8 ns

Sequential Delay Example (Load = 30 pF)



INPUT DELAY + REG SET-UP + CLOCK TO OUTPUT + OUTPUT DELAY = 12.1 ns

High-Drive Delay Example



INPUT DELAY + COMBINATORIAL DELAY + OUTPUT DELAY = 10.2 ns



Ordering Information

Speed Grade	Ordering Code	Package Name	Package Type	Operating Range
3	CY7C381-3JC	J67	44-Lead Plastic Leaded Chip Carrier	Commercial
2	CY7C381-2JC	J67	44-Lead Plastic Leaded Chip Carrier	Commercial
	CY7C381-2JI	J67	44-Lead Plastic Leaded Chip Carrier	Industrial
1	CY7C381-1JC	J67	44-Lead Plastic Leaded Chip Carrier	Commercial
	CY7C381-1JI	J67	44-Lead Plastic Leaded Chip Carrier	Industrial
0	CY7C381-0JC	J67	44-Lead Plastic Leaded Chip Carrier	Commercial
	CY7C381-0JI	J67	44-Lead Plastic Leaded Chip Carrier	Industrial

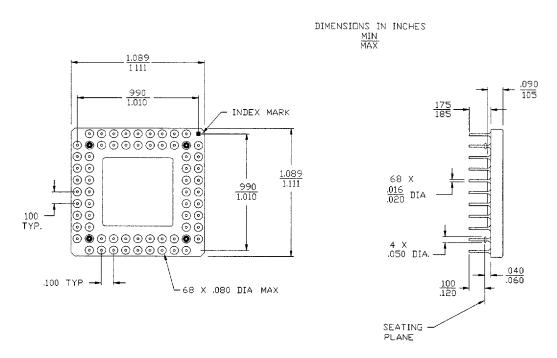
Speed Grade	Ordering Code	Package Name	Package Type	Operating Range
3	CY7C382-3GC	G68	68-Pin Grid Array (Cavity Down)	Commercial
	CY7C382-3JC	J81	68-Lead Plastic Leaded Chip Carrier	
2	CY7C382-2GC	G68	68-Pin Grid Array (Cavity Down)	Commercial
	CY7C382-2JC	J81	68-Lead Plastic Leaded Chip Carrier	
	CY7C382-2GI	G68	68-Pin Grid Array (Cavity Down)	Industrial
	CY7C382-2JI	J 81	68-Lead Plastic Leaded Chip Carrier	
1	CY7C382-1GC	G68	68-Pin Grid Array (Cavity Down)	Commercial
	CY7C382-1JC	J 81	68-Lead Plastic Leaded Chip Carrier	
	CY7C382-1GI	G68	68-Pin Grid Array (Cavity Down)	Industrial
	CY7C382-1JI	J81	68-Lead Plastic Leaded Chip Carrier	1
0	CY7C382-0GC	G68	68-Pin Grid Array (Cavity Down)	Commercial
	CY7C382-0JC	J 81	68-Lead Plastic Leaded Chip Carrier	
	CY7C382-0GI	G68	68-Pin Grid Array (Cavity Down)	Industrial
	CY7C382-0JI	J 81	68-Lead Plastic Leaded Chip Carrier	

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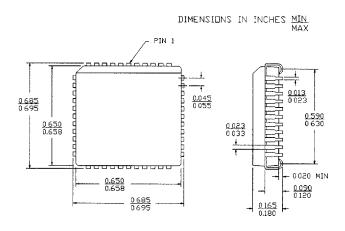


Package Diagrams

68-Pin Grid Array (Cavity Down) G68



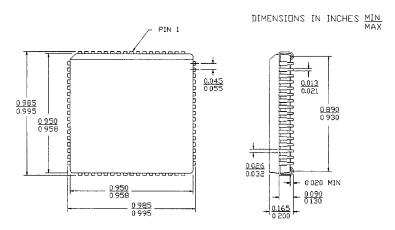
44-Lead Plastic Leaded Chip Carrier J67





Package Diagrams (continued)

68-Lead Plastic Leaded Chip Carrier J81



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